nexperia

Quarterly Reliability Monitoring Results

Quarters: Q1/2022 to Q4/2023

Based on structural	similarity
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Supplier		User Part Number				
Nexperia B.V.		PMEG6030CER-Q				
Name of La	aboratory	Part Description				
Assembly reliability labs		Nexperia DHAM	Schottky			
		SMD package				
	AEC-Q101 Test	Test Conditions	Duration	# Lots	# Quantity	# Rejects
	TEST				. ,	
	Pre- and Post-Stress					
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below
		JESD22-A113				
		Bake Tamb = 125 °C	24 hours			
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours			
# A1	Preconditioning	Reflow soldering	3 cycles	1514	64430	0
		MIL-STD-750-1				
	HTRB	M1038 Method A				
		Tj = Tjmax, Vr = 100% of max. datasheet				
# B1	Bias	reverse voltage ^[1]	1000 hours	206	9320	0
						-
	тс	JESD22-A104				
# A4	Temperature Cycling	-65 °C to Timax, not to exceed 150°C	1000 cycles	311	14080	0
	· · · · · · · · · · · · · · · · · · ·		1000 Cycles	511	11000	0
	UHAST	JESD22-A118				
# A3 or	Unbiased HAST	Tamb = 130 °C, RH = 85 %				
" /\3 0 1	onblased fixes f		– 96 hours	311	14080	0
# AQ II	AC	JESD22-A102 Tamb = 121 °C, RH = 100 %				
	Autoclave	Pressure = 205 kPa (29.7 psia)				
# A3 alt	Autociave	Plessure = 203 kPa (29.7 psia)				
		JESD22-A101				
	H3TRB	Tamb = $85 ^{\circ}$ C, RH = 85% , VR = 80% of				
	High Humidity High	rated reverse voltage ^{[1], [2]}	10001		1 1000	<u>^</u>
# A2 alt	remperature Reverse Blas		1000 hours	311	14080	0
		MIL-STD-750 Method 1037				
	IOL	ton = toff, devices powered to insure $\Delta T j$ =				
# A5	Intermittent Operating Life	100 °C for 15000 cycles	1000 hours	312	14120	0
	RSH	JESD22-A111				
# C8	Resistance to Solder Heat	260 °C ± 5 °C	10 s	269	8070	0
	SD					
# C10	Solderability	J-STD-002		222	6660	0

[1] The physical limitations of Schottky diodes have to be considered (thermal runaway).[2] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Schottky	9320	0	0,46	2,19E+09

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